

*A1*  
*Con't*

result with a reference value to make a determination as to whether or not the result is good. However, in the conventional example described above, beside the image processing apparatus, an auto-focusing unit, a microscope, and electron beams are required, whereby the examination is conducted for each one of the through holes, or with an expanded image that is expanded at a high level of magnification.

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### IN THE CLAIMS

Please amend the claims in accordance with the following rewritten claims in clean form. Applicants include herewith an Attachment for Claim Amendments showing a marked up version of each amended claim.

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*A2*

Claim 1. (AMENDED) A through hole examination method comprising:  
irradiating light from one side of a work piece having a through hole; and  
detecting passing light by imaging the passing light from another side of  
the work piece by a sensor camera having a plurality of imaging elements,  
wherein the examination is conducted by imaging with an imaging focal  
point of the sensor camera being shifted with respect to a surface of the work piece.

Claim 2. (AMENDED) A through hole examination method comprising:  
irradiating light from one side of a work piece having a plurality of through  
holes;  
imaging and detecting passing light from another side of the work piece by  
a sensor camera having a plurality of imaging elements,